## Notice of References Cited Application/Control No. 10/822,299 DEARDURFF ET AL. Examiner Thu Khanh T. Nguyen Applicant(s)/Patent Under Reexamination DEARDURFF ET AL. Page 1 of 1

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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